Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination BAEK ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,657,374	12-2003	Nagasawa et al.	313/477R
	В	US-6,800,993	10-2004	Tho et al.	313/477R
	C	US-6,812,631	11-2004	Murakami, Toshihide	313/477R
	D	US-2003/0025439	02-2003	Fujita, Kenji	313/477.00R
	ш	US-2003/0168963	09-2003	Baek, Jae-Seung	313/477.00R
	F	US-2004/0051437	03-2004	Kim, Hyuk Dong	313/440
	G	US-2005/0052113	03-2005	Kim, Sung Hun	313/477.00R
	H	US-			
	-	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000306528 A	11-2000	Japan	MASHITA et al.	H01J 29/87
	0	KR 2002076830 A	10-2002	Korea, Republic	DO et al.	H01J 29/02
	Р	KR 2004044067 A	05-2004	Korea, Republic	CHO et al.	H01J 29/87
	α					
	R					
	Ø					
	Τ					

NON-PATENT DOCUMENTS

*	<u> </u>	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	x						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.